Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/626,560	UMEDA ET AL.
Examiner	Art Unit
Shih-wen Hsieh	2861

	SEAR	CHED	
Class	Subclass	Date	Examiner
updated	updated	3/3/2005	SWH

INI	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
347	30,29	3/3/2005	SWH SWH
347	32	3/3/2005	SWH '
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
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